PRELIMINARY DATA SHEET

HETERO JUNCTION FIELD EFFECT TRANSISTOR NE23383B

L to X BAND SUPER LOW NOISE AMPLIFIER N-CHANNEL HJ-FET

DESCRIPTION

NEC

The NE23383B is a Herero Junction FET that utilizes the hetero junction to create high mobility electrons.

FEATURES

- Super Low Noise Figure & High Associated Gain NF = 0.35 dB TYP., G_a = 15.0 dB TYP. at f = 4 GHz
- Gate Width: $W_g = 280 \ \mu m$
- Hermetic sealed ceramic package
- High reliability

ABSOLUTE MAXIMUM RATINGS (T_A = $25 \degree$ C)

Drain to Source Voltage	b∧s	4.0	V
Gate to Source Voltage	¥d∕s	-3.0	V
Drain Current	d	IDSS	mΑ
Total Power Dissipation	t₽₹	165	mW
Channel Temperature	đh	175	°C
Storage Temperature	₫tg	-65 to +175	°C



RECOMMENDED OPERATING CONDITION (TA = 25 °C)

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	Unit
Drain to Source Voltage	blé		2	3	V
Drain Current	Ь		10	20	mA
Input Power	₽			0	dBm

ELECTRICAL CHARACTERISTICS (TA = 25 °C)

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS
Gate to Source Leak Current	lgso		0.5	10	μA	$V_{GS} = -3 V$
Gate to Drain Leak Current	Igdo		0.5	10	μA	$V_{GD} = -3 V$
Saturated Drain Current	loss	15	40	80	mA	$V_{DS} = 2 V, V_{GS} = 0 V$
Gate to Source Cut off Voltage	VGS(off)	-0.2	-0.8	-2.0	V	$V_{DS} = 2 V, I_{D} = 100 \mu A$
Transconductance	gm	45	70		mS	V _{DS} = 2 V, I _D = 10 mA
Noise Figure	NF		0.35	0.45	dB	V _{DS} = 2 V, I _D = 10 mA
Associated Gain	Ga	13.0	15.0		dB	f = 4 GHz



TYPICAL CHARACTERISTICS (TA = 25 °C)



MSG. =
$$\frac{|S_{21}|}{|S_{12}|}$$

MAG. = $\frac{|S_{21}|}{|S_{12}|}$ (K ± $\sqrt{K^2 - 1}$)
 $A = S_{11} \cdot S_{22} - S_{21} \cdot S_{12}$

S-Parameter

MAG. AND ANG. VDS = 2 V, ID = 10 mA

FREQUENCY	:	S11	5	S 21	S	S 12	:	S22	К
GHz	MAG.	ANG.	MAG.	ANG.	MAG.	ANG.	MAG.	ANG.	
		(deg.)		(deg.)		(deg.)		(deg.)	
2.0	.96	-39.94	5.00	141.49	.03	66.70	.52	-25.96	.22
3.0	.91	-53.81	4.54	125.98	.04	58.07	.54	-38.70	.36
4.0	.88	-64.11	4.07	113.15	.05	52.54	.54	-44.90	.46
5.0	.80	-74.58	3.85	100.67	.05	47.00	.57	-51.85	.67
6.0	.77	-85.67	3.73	88.48	.06	42.12	.51	-57.28	.76
7.0	.69	-98.42	3.71	75.46	.07	36.19	.46	-66.10	.90
8.0	.63	-115.67	3.64	60.60	.08	28.39	.41	-80.09	.98
9.0	.59	-132.86	3.44	46.21	.08	21.00	.40	-95.43	1.07
10.0	.57	-145.83	3.18	32.90	.08	13.97	.41	-109.27	1.12
11.0	.55	-154.21	2.97	22.06	.08	7.90	.43	-115.64	1.26
12.0	.54	-164.09	2.91	10.84	.08	6.58	.46	-120.71	1.24
13.0	.53	-179.26	2.88	-2.27	.08	3.61	.47	-131.41	1.15
14.0	.53	169.19	2.78	-16.05	.08	-4.59	.46	-146.02	1.20
15.0	.53	157.02	2.65	-29.31	.08	-9.21	.49	-156.04	1.18
16.0	.53	149.49	2.69	-41.55	.08	-10.08	.55	-166.37	.98
17.0	.52	136.67	2.69	-57.64	.09	-17.82	.58	177.96	.85
18.0	.50	117.26	2.59	-76.16	.09	-30.52	.61	159.46	.81

Noise Parameters

 $V_{DS} = 2 V$, $I_{D} = 10 mA$

Erog (GHz)	NE(dB)	G. (dB)	Га	R /50	
rieq (Griz)			MAG.	ANG. (deg.)	R₩30
2.0	0.32	16.0	0.90	26	0.35
4.0	0.35	15.0	0.80	51	0.29
6.0	0.41	13.7	0.70	75	0.22
8.0	0.50	12.6	0.61	101	0.15
10.0	0.62	11.5	0.53	127	0.09
12.0	0.75	10.5	0.48	154	0.05
14.0	0.88	9.6	0.45	-178	0.05
16.0	1.02	8.8	0.44	-147	0.07
18.0	1.15	8.0	0.48	-115	0.14

RECOMMENDED SOLDERING CONDITIONS

The following conditions (see table below) must be met when soldering this product.

Please consult with our sales offices in case other soldering process is used, or in case soldering is done under different conditions.

<TYPES OF SURFACE MOUNT DEVICE>

For more details, refer to our document "SEMICONDUCTOR DEVICE MOUNTING TECHNOLOGY MANUAL" (C10535E)

Soldering process	Soldering conditions	Symbol
Partial heating method	Terminal temperature: 230 °C or below, Flow time: 10 seconds or below, Exposure limit ^{Note} : None	

Note: Exposure limit before soldering after dry-pack package is opened.

Storage conditions: 25 °C and relative humidity at 65 % or less.

Caution: Do not apply more than a single process at once, except for "Partial heating method".

PRECAUTION: Avoid high static voltage and electric fields, because this device is Hetero Junction field effect transistor with shottky barrier gate.

Caution

The Great Care must be taken in dealing with the devices in this guide. The reason is that the material of the devices is GaAs (Gallium Arsenide), which is designated as harmful substance according to the law concerned. Keep the law concerned and so on, especially in case of removal. [MEMO]

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- Special: Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)
- Specific: Aircrafts, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems or medical equipment for life support, etc.

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Anti-radioactive design is not implemented in this product.